


<b>Search Notes</b>  	<b>Application/Control No.</b>  10578762	<b>Applicant(s)/Patent Under Reexamination</b>  TAN ET AL.
	<b>Examiner</b>  Bashaw, Heidi M	<b>Art Unit</b>  4138

SEARCHED			
Class	Subclass	Date	Examiner
433	10-11	10.24.2007	HMB
	Updated	4.11.2008	HMB

SEARCH NOTES		
Search Notes	Date	Examiner
W/ Wilson on above search	10.24.2007	HMB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner